

<b>Notice of References Cited</b>	Application/Control No. 10/760,149		Applicant(s)/Patent Under Reexamination MIEHER ET AL.	
	Examiner Juan D. Valentin II		Art Unit 2877	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,884,552 B2	04-2005	Mieher et al.	356/401
*	B	US-2003/0048458 A1	03-2003	Mieher et al.	356/601
*	C	US-6,879,406 B1	04-2005	Rangarajan et al.	356/625
*	D	US-2004/0114132 A1	06-2004	Den Boef et al.	356/124
*	E	US-6,429,930 B1	08-2002	Littau et al.	356/124
*	F	US-6,650,422 B2	11-2003	Singh et al.	356/601
*	G	US-6,614,540 B1	09-2003	Stirton, James Broc	356/630
*	H	US-7,079,235 B2	07-2006	Lehman, Yonatan	356/237.1
*	I	US-6,466,314 B1	10-2002	Lehman, Yonatan	356/237.1
*	J	US-6,559,953 B1	05-2003	Davids, Paul S.	356/521
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.